**15th Canadian Powder Diffraction Workshop (CPDW15)**

**Registration Form**

*Hybrid workshop* *October 11th – 14th, 2022*

|  |  |
| --- | --- |
| **First name** |  |
| **Last name** |  |
| **Organization** |  |
| **Address** |  |
| **Email address** |  |
| **Research area**  (enter 3 keywords) | 1  2  3 |
| **Affiliation** | Academic (registration fee $50 per person)  Non-academic (registration fee $200 per person) |
| **Instructions for submission:**  Please fill in this form and send it to [Bussaraporn.patarachao@nrc-cnrc.gc.ca](mailto:Bussaraporn.patarachao@nrc-cnrc.gc.ca) (Bussaraporn Patarachao) as soon as possible (before September 30th, 2022). Please do not send funds for registration until you have been notified of acceptance. | |
| **Instructions for submission:**  Registration will be limited to 200 participants. Number of participants for the ‘in-person’ hands on software tutorials will also be limited depending on locations. Priority for the ‘in-person’ sessions will be determined by the organizers. | |

**If you are interested in attending ‘in-person’ hands on tutorial, please complete the form below.**

|  |  |  |
| --- | --- | --- |
| Select location | Select Software | Do you have access to software and license (Y/N)? |
| McMaster University | EVA (Bruker)  TOPAS (Bruker) |  |
| University of British Columbia | EVA (Bruker)  TOPAS (Bruker)  HighscorePlus (Malvern-Panalytical) |  |
| University of Saskatchewan | GSAS-II (Argonne National Labs) | software available online; no license required |
| Data Acquisition: Would you like to have data collected on a sample for the workshop? | | |

*\* There are a limited number of 'in-person' spots for the hands-on tutorial sessions. Priority will be determined by the organizers.*

**Hands on Tutorial Survey (sessions: Oct. 13th – 14th, 2022 at 14:20-16:20 EST)**

|  |  |
| --- | --- |
| **Topic of Interest\***  Indicate priority 1, 2, 3... (1 for highest priority) | |
| Phase Identification |  |
| Data handling for multiple scans |  |
| % Crystallinity |  |
| Indexing |  |
| Rietveld refinement |  |
| Quantitative Phase Analysis – Rietveld |  |
| Whole Pattern Refinement |  |
| Crystallite size and strain |  |
| Instrument profile parameters |  |
| Simulating Powder Diffraction |  |
| LeBail intensity extraction |  |
| Others – please specify: | |

*\* Only 1 or 2 topics will be touched on. If there is a high interest in a topic the presenters will consider this as a tutorial topic.*